

Fiber Optic Industry News

Industry Wide Round Robin on Return Loss Measurements in TIA

December 17, 2004

As part of this Round Robin, Return Loss artifacts will be sent to participating companies for measurement. Finally comparing all results will provide insight on how well Return Loss measurements agree when conducted by different people using different instruments. Return Loss is together with Insertion Loss possibly the most commonly measured parameter when it comes to characterizing fiber optic components.

Participation in this Round Robin is highly encouraged to increase the statistical significance of the measurement results. Specific information in regards to the type of test samples that will be sent to each participant and the detailed procedure for conducting the Return Loss measurements can be obtained by contacting either of the following two individuals”

Tim Drapela, NIST, Ph: 303-496-5858 e-mail: drapela@boulder.nist.gov

Lorenz Cartellieri, Experior Photonics, Ph: 805-499-3000 e-mail: lcartellieri@experiorphotonics.com

The Return Loss artifacts (test samples) are currently being prepared and are expected to be completed by February 2005.

The measurement and reporting instructions for the Round Robin participants are expected to be finalized at the TIA meeting Jan. 24, 2005 - Jan. 27, 2005 in Phoenix AZ. For a copy of the meeting schedule please visit:

<http://www.tiaonline.org/standards/sfg/committee.cfm?comm=fo%2D4&name=Fiber%20Optics>

Discussions regarding the schedule and the begin of the Round Robin will be held as part of the Round Robin working group FO-4.5.1 on Wednesday Jan. 26 afternoon. A draft of the instructions is available from Lorenz Cartellieri at Experior Photonics (see above).

For more information on standardization efforts and information regarding the development of test and measurement standards for the fiber optics industry, please visit www.tiaonline.org

Current List of Participants for the Round Robin are:

INTERNATIONAL Participant	Contact Person	DOMESTIC Participant	Contact Person
Acterna		ADC	
NTT-AT		Advanced Interconnect	Andrei Vankov
Yokogawa		Corning	
Anritsu	Dr. Adachi	EXFO	Marc Breton
National Physical Laboratory	Dr. Sakamoto	JDS Uniphase	Alain Nicolle
Kingfisher International	Tim Jones	Experior Photonics	Lorenz Cartellieri
	Brian Crook	NAVSEA Metrology Lab	Harold Glick
		NAVAIR Test Lab	Juock Namkung
		NIST	Tim Drapela
		Tempo/Opto-Electronics	Terri Tricker
		Taliescent	Eugene Rudkevich
		Tyco Electronics	
		US Conec	Matt Brown